

<b>Notice of References Cited</b>	Application/Control No. 10/768,146	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0083338	04-2004	Moriwaki et al.	711/114
	B	US-2003/0221070	11-2003	Minowa et al.	711/147
	C	US-5,155,835	10-1992	Belsan, Jay S.	711/114
	D	US-5,077,736	12-1991	Dunphy et al.	714/7
	E	US-2004/0153691	08-2004	Fujimoto et al.	714/003
	F	US-2003/0204683	10-2003	Okumoto et al.	711/147
	G	US-6,385,114	05-2002	Abe et al.	365/226
	H	US-2005/0097132	05-2005	Cochran et al.	707/104.1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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